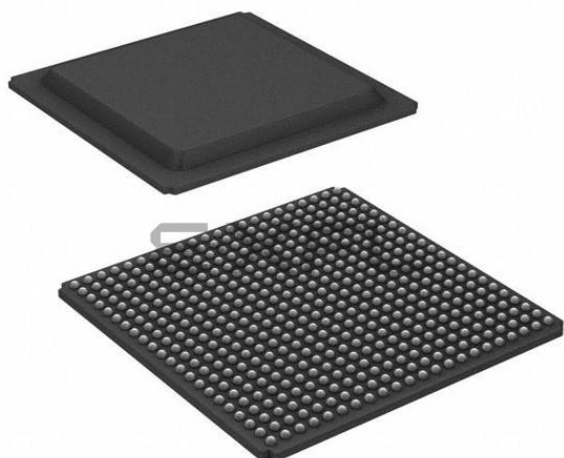




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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	7911
Number of Logic Elements/Cells	101261
Total RAM Bits	4939776
Number of I/O	326
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	484-BBGA
Supplier Device Package	484-FBGA (23x23)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc6slx100-l1fgg484i

Quiescent Current

Typical values for quiescent supply current are specified at nominal voltage, 25°C junction temperatures (T_j). Quiescent supply current is specified by speed grade for Spartan-6 devices. Xilinx recommends analyzing static power consumption using the XPOWER™ Estimator (XPE) tool (download at <http://www.xilinx.com/power>) for conditions other than those specified in Table 5.

Table 5: Typical Quiescent Supply Current

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
I_{CCINTQ}	Quiescent V_{CCINT} supply current	LX4	4.0	4.0	4.0	2.4	mA
		LX9	4.0	4.0	4.0	2.4	mA
		LX16	6.0	6.0	6.0	4.0	mA
		LX25	11.0	11.0	11.0	6.6	mA
		LX25T	11.0	11.0	11.0	N/A	mA
		LX45	15.0	15.0	15.0	9.0	mA
		LX45T	15.0	15.0	15.0	N/A	mA
		LX75	29.0	29.0	29.0	17.4	mA
		LX75T	29.0	29.0	29.0	N/A	mA
		LX100	36.0	36.0	36.0	21.6	mA
		LX100T	36.0	36.0	36.0	N/A	mA
		LX150	51.0	51.0	51.0	31.0	mA
		LX150T	51.0	51.0	51.0	N/A	mA
I_{CCOQ}	Quiescent V_{CCO} supply current	LX4	1.0	1.0	1.0	1.0	mA
		LX9	1.0	1.0	1.0	1.0	mA
		LX16	2.0	2.0	2.0	2.0	mA
		LX25	2.0	2.0	2.0	2.0	mA
		LX25T	2.0	2.0	2.0	N/A	mA
		LX45	3.0	3.0	3.0	3.0	mA
		LX45T	3.0	3.0	3.0	N/A	mA
		LX75	4.0	4.0	4.0	4.0	mA
		LX75T	4.0	4.0	4.0	N/A	mA
		LX100	5.0	5.0	5.0	5.0	mA
		LX100T	5.0	5.0	5.0	N/A	mA
		LX150	7.0	7.0	7.0	7.0	mA
		LX150T	7.0	7.0	7.0	N/A	mA

Table 5: Typical Quiescent Supply Current (Cont'd)

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
I _{CCAUXQ}	Quiescent V _{CCAUX} supply current	LX4	2.5	2.5	2.5	2.5	mA
		LX9	2.5	2.5	2.5	2.5	mA
		LX16	3.0	3.0	3.0	3.0	mA
		LX25	4.0	4.0	4.0	4.0	mA
		LX25T	4.0	4.0	4.0	N/A	mA
		LX45	5.0	5.0	5.0	5.0	mA
		LX45T	5.0	5.0	5.0	N/A	mA
		LX75	7.0	7.0	7.0	7.0	mA
		LX75T	7.0	7.0	7.0	N/A	mA
		LX100	9.0	9.0	9.0	9.0	mA
		LX100T	9.0	9.0	9.0	N/A	mA
		LX150	12.0	12.0	12.0	12.0	mA
		LX150T	12.0	12.0	12.0	N/A	mA

Notes:

- Typical values are specified at nominal voltage, 25°C junction temperatures (T_j). Industrial (I) grade devices have the same typical values as commercial (C) grade devices at 25°C, but higher values at 100°C. Use the XPE tool to calculate 100°C values. Nominal V_{CCINT} is 1.20V; use the XPE tool to calculate 1.23V values for the nominal V_{CCINT} of the extended performance range.
- Typical values are for blank configured devices with no output current loads, no active input pull-up resistors, all I/O pins are 3-state and floating.
- If differential signaling is used, more accurate quiescent current estimates can be obtained by using the XPOWER Estimator (XPE) or XPOWER Analyzer (XPA) tools.

Table 6: Power Supply Ramp Time

Symbol	Description	Speed Grade	Ramp Time	Units
V _{CCINTR}	Internal supply voltage ramp time	-3, -3N, -2	0.20 to 50.0	ms
		-1L	0.20 to 40.0	ms
V _{CCO2} ⁽¹⁾	Output drivers bank 2 supply voltage ramp time	All	0.20 to 50.0	ms
V _{CCAUXR}	Auxiliary supply voltage ramp time	All	0.20 to 50.0	ms

Notes:

- The minimum V_{CCO2} for power-on reset and configuration is 1.65V.
- Spartan-6 FPGAs require a certain amount of supply current during power-on to insure proper device initialization. The actual current consumed depends on the power-on ramp rate of the power supply. Use the XPOWER Estimator (XPE) or XPOWER Analyzer (XPA) tools to estimate current drain on these supplies. Spartan-6 devices do not have a required power-on sequence.

In Table 9 and Table 10, values for V_{IL} and V_{IH} are recommended input voltages. Values for I_{OL} and I_{OH} are guaranteed over the recommended operating conditions at the V_{OL} and V_{OH} test points. Only selected standards are tested. These are chosen to ensure that all standards meet their specifications. The selected standards are tested at a minimum V_{CCO} with the respective V_{OL} and V_{OH} voltage levels shown. Other standards are sample tested.

Table 9: Single-Ended I/O Standard DC Input and Output Levels

I/O Standard	V_{IL}		V_{IH}		V_{OL}	V_{OH}	I_{OL}	I_{OH}
	V, Min	V, Max	V, Min	V, Max	V, Max	V, Min	mA	mA
LVTTTL	−0.5	0.8	2.0	4.1	0.4	2.4	Note 2	Note 2
LVC MOS33	−0.5	0.8	2.0	4.1	0.4	$V_{CCO} - 0.4$	Note 2	Note 2
LVC MOS25	−0.5	0.7	1.7	4.1	0.4	$V_{CCO} - 0.4$	Note 2	Note 2
LVC MOS18	−0.5	0.38	0.8	4.1	0.45	$V_{CCO} - 0.45$	Note 2	Note 2
LVC MOS18 (−1L)	−0.5	0.33	0.71	4.1	0.45	$V_{CCO} - 0.45$	Note 2	Note 2
LVC MOS18_JEDEC	−0.5	35% V_{CCO}	65% V_{CCO}	4.1	0.45	$V_{CCO} - 0.45$	Note 2	Note 2
LVC MOS15	−0.5	0.38	0.8	4.1	25% V_{CCO}	75% V_{CCO}	Note 3	Note 3
LVC MOS15 (−1L)	−0.5	0.33	0.71	4.1	25% V_{CCO}	75% V_{CCO}	Note 3	Note 3
LVC MOS15_JEDEC	−0.5	35% V_{CCO}	65% V_{CCO}	4.1	25% V_{CCO}	75% V_{CCO}	Note 3	Note 3
LVC MOS12	−0.5	0.38	0.8	4.1	0.4	$V_{CCO} - 0.4$	Note 4	Note 4
LVC MOS12 (−1L)	−0.5	0.33	0.71	4.1	0.4	$V_{CCO} - 0.4$	Note 4	Note 4
LVC MOS12_JEDEC	−0.5	35% V_{CCO}	65% V_{CCO}	4.1	0.4	$V_{CCO} - 0.4$	Note 4	Note 4
PCI33_3	−0.5	30% V_{CCO}	50% V_{CCO}	$V_{CCO} + 0.5$	10% V_{CCO}	90% V_{CCO}	1.5	−0.5
PCI66_3	−0.5	30% V_{CCO}	50% V_{CCO}	$V_{CCO} + 0.5$	10% V_{CCO}	90% V_{CCO}	1.5	−0.5
I2C	−0.5	25% V_{CCO}	70% V_{CCO}	4.1	20% V_{CCO}	—	3	—
SMBUS	−0.5	0.8	2.1	4.1	0.4	—	4	—
SDIO	−0.5	12.5% V_{CCO}	75% V_{CCO}	4.1	12.5% V_{CCO}	75% V_{CCO}	0.1	−0.1
MOBILE_DDR	−0.5	20% V_{CCO}	80% V_{CCO}	4.1	10% V_{CCO}	90% V_{CCO}	0.1	−0.1
HSTL_I	−0.5	$V_{REF} - 0.1$	$V_{REF} + 0.1$	4.1	0.4	$V_{CCO} - 0.4$	8	−8
HSTL_II	−0.5	$V_{REF} - 0.1$	$V_{REF} + 0.1$	4.1	0.4	$V_{CCO} - 0.4$	16	−16
HSTL_III	−0.5	$V_{REF} - 0.1$	$V_{REF} + 0.1$	4.1	0.4	$V_{CCO} - 0.4$	24	−8
HSTL_I_18	−0.5	$V_{REF} - 0.1$	$V_{REF} + 0.1$	4.1	0.4	$V_{CCO} - 0.4$	11	−11
HSTL_II_18	−0.5	$V_{REF} - 0.1$	$V_{REF} + 0.1$	4.1	0.4	$V_{CCO} - 0.4$	22	−22
HSTL_III_18	−0.5	$V_{REF} - 0.1$	$V_{REF} + 0.1$	4.1	0.4	$V_{CCO} - 0.4$	30	−11
SSTL3_I	−0.5	$V_{REF} - 0.2$	$V_{REF} + 0.2$	4.1	$V_{TT} - 0.6$	$V_{TT} + 0.6$	8	−8
SSTL3_II	−0.5	$V_{REF} - 0.2$	$V_{REF} + 0.2$	4.1	$V_{TT} - 0.8$	$V_{TT} + 0.8$	16	−16
SSTL2_I	−0.5	$V_{REF} - 0.15$	$V_{REF} + 0.15$	4.1	$V_{TT} - 0.61$	$V_{TT} + 0.61$	8.1	−8.1
SSTL2_II	−0.5	$V_{REF} - 0.15$	$V_{REF} + 0.15$	4.1	$V_{TT} - 0.81$	$V_{TT} + 0.81$	16.2	−16.2
SSTL18_I	−0.5	$V_{REF} - 0.125$	$V_{REF} + 0.125$	4.1	$V_{TT} - 0.47$	$V_{TT} + 0.47$	6.7	−6.7
SSTL18_II	−0.5	$V_{REF} - 0.125$	$V_{REF} + 0.125$	4.1	$V_{TT} - 0.60$	$V_{TT} + 0.60$	13.4	−13.4
SSTL15_II	−0.5	$V_{REF} - 0.1$	$V_{REF} + 0.1$	4.1	$V_{TT} - 0.4$	$V_{TT} + 0.4$	13.4	−13.4

Notes:

1. Tested according to relevant specifications.
2. Using drive strengths of 2, 4, 6, 8, 12, 16, or 24 mA.
3. Using drive strengths of 2, 4, 6, 8, 12, or 16 mA.
4. Using drive strengths of 2, 4, 6, 8, or 12 mA.
5. For more information, refer to [UG381](#): *Spartan-6 FPGA SelectIO Resources User Guide*.

Switching Characteristics

All values represented in this data sheet are based on these speed specifications: v1.20 for -3, -3N, and -2; and v1.08 for -1L. Switching characteristics are specified on a per-speed-grade basis and can be designated as Advance, Preliminary, or Production. Each designation is defined as follows:

Advance

These specifications are based on simulations only and are typically available soon after device design specifications are frozen. Although speed grades with this designation are considered relatively stable and conservative, some under-reporting might still occur.

Preliminary

These specifications are based on complete ES (engineering sample) silicon characterization. Devices and speed grades with this designation are intended to give a better indication of the expected performance of production silicon. The probability of under-reporting delays is greatly reduced as compared to Advance data.

Production

These specifications are released once enough production silicon of a particular device family member has been characterized to provide full correlation between specifications and devices over numerous production lots. There is no under-reporting of delays, and customers receive formal notification of any subsequent changes. Typically, the slowest speed grades transition to Production before faster speed grades.

All specifications are always representative of worst-case supply voltage and junction temperature conditions.

Since individual family members are produced at different times, the migration from one category to another depends completely on the status of the fabrication process for each device.

The -1L speed grade refers to the lower-power Spartan-6 devices. The -3N speed grade refers to the Spartan-6 devices that do not support MCB functionality.

[Table 26](#) correlates the current status of each Spartan-6 device on a per speed grade basis.

Testing of Switching Characteristics

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values.

For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer and back-annotate to the simulation net list. Unless otherwise noted, values apply to all Spartan-6 devices.

Table 26: Spartan-6 Device Speed Grade Designations

Device	Speed Grade Designations		
	Advance	Preliminary	Production
XC6SLX4 ⁽¹⁾			-3, -2, -1L
XC6SLX9			-3, -3N, -2, -1L
XC6SLX16			-3, -3N, -2, -1L
XC6SLX25			-3, -3N, -2, -1L
XC6SLX25T			-3, -3N, -2
XC6SLX45			-3, -3N, -2, -1L
XC6SLX45T			-3, -3N, -2
XC6SLX75			-3, -3N, -2, -1L
XC6SLX75T			-3, -3N, -2
XC6SLX100			-3, -3N, -2, -1L
XC6SLX100T			-3, -3N, -2
XC6SLX150			-3, -3N, -2, -1L
XC6SLX150T			-3, -3N, -2
XA6SLX4			-3, -2
XA6SLX9			-3, -2
XA6SLX16			-3, -2
XA6SLX25			-3, -2
XA6SLX25T			-3, -2
XA6SLX45			-3, -2
XA6SLX45T			-3, -2
XA6SLX75			-3, -2
XA6SLX75T			-3, -2
XA6SLX100			-2
XQ6SLX75			-2, -1L
XQ6SLX75T			-3, -2
XQ6SLX150			-2, -1L
XQ6SLX150T			-3, -2

Notes:

1. The XC6SLX4 is not available in the -3N speed grade.

Table 28: IOB Switching Characteristics for the Commercial (XC) Spartan-6 Devices (Cont'd)

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	-3	-3N	-2	-1L ⁽¹⁾	-3	-3N	-2	-1L ⁽¹⁾	-3	-3N	-2	-1L ⁽¹⁾	
PPDS_33	1.17	1.29	1.42	1.68	1.57	1.71	1.91	2.43	3000	3000	3000	3000	ns
PPDS_25	1.01	1.13	1.26	1.56	1.68	1.82	2.02	2.47	3000	3000	3000	3000	ns
PCI33_3	1.07	1.19	1.32	1.57 ⁽²⁾	3.51	3.65	3.85	4.38 ⁽²⁾	3.51	3.65	3.85	4.38 ⁽¹⁾	ns
PCI66_3	1.07	1.19	1.32	1.57 ⁽²⁾	3.53	3.67	3.87	4.39 ⁽²⁾	3.53	3.67	3.87	4.39 ⁽¹⁾	ns
DISPLAY_PORT	1.02	1.14	1.27	1.56	3.15	3.29	3.49	4.08	3.15	3.29	3.49	4.08	ns
I2C	1.33	1.45	1.58	1.82	11.56	11.70	11.90	12.52	11.56	11.70	11.90	12.52	ns
SMBUS	1.33	1.45	1.58	1.82	11.56	11.70	11.90	12.52	11.56	11.70	11.90	12.52	ns
SDIO	1.36	1.48	1.61	1.84	2.64	2.78	2.98	3.60	2.64	2.78	2.98	3.60	ns
MOBILE_DDR	0.94	1.06	1.19	1.43	2.35	2.49	2.69	3.31	2.35	2.49	2.69	3.31	ns
HSTL_I	0.90	1.02	1.15	1.39	1.66	1.80	2.00	2.62	1.66	1.80	2.00	2.62	ns
HSTL_II	0.91	1.03	1.16	1.40	1.72	1.86	2.06	2.68	1.72	1.86	2.06	2.68	ns
HSTL_III	0.95	1.07	1.20	1.44	1.67	1.81	2.01	2.61	1.67	1.81	2.01	2.61	ns
HSTL_I_18	0.94	1.06	1.19	1.43	1.77	1.91	2.11	2.73	1.77	1.91	2.11	2.73	ns
HSTL_II_18	0.94	1.06	1.19	1.43	1.85	1.99	2.19	2.81	1.85	1.99	2.19	2.81	ns
HSTL_III_18	0.99	1.11	1.24	1.47	1.79	1.93	2.13	2.72	1.79	1.93	2.13	2.72	ns
SSTL3_I	1.58	1.70	1.83	2.16	1.83	1.97	2.17	2.72	1.83	1.97	2.17	2.72	ns
SSTL3_II	1.58	1.70	1.83	2.16	2.01	2.15	2.35	2.94	2.01	2.15	2.35	2.94	ns
SSTL2_I	1.30	1.42	1.55	1.87	1.77	1.91	2.11	2.69	1.77	1.91	2.11	2.69	ns
SSTL2_II	1.30	1.42	1.55	1.88	1.86	2.00	2.20	2.82	1.86	2.00	2.20	2.82	ns
SSTL18_I	0.92	1.04	1.17	1.41	1.63	1.77	1.97	2.59	1.63	1.77	1.97	2.59	ns
SSTL18_II	0.92	1.04	1.17	1.41	1.66	1.80	2.00	2.62	1.66	1.80	2.00	2.62	ns
SSTL15_II	0.92	1.04	1.17	1.41	1.67	1.81	2.01	2.63	1.67	1.81	2.01	2.63	ns
DIFF_HSTL_I	0.94	1.06	1.19	1.46	1.77	1.91	2.11	2.62	1.77	1.91	2.11	2.62	ns
DIFF_HSTL_II	0.93	1.05	1.18	1.45	1.72	1.86	2.06	2.54	1.72	1.86	2.06	2.54	ns
DIFF_HSTL_III	0.93	1.05	1.18	1.46	1.69	1.83	2.03	2.53	1.69	1.83	2.03	2.53	ns
DIFF_HSTL_I_18	0.97	1.09	1.22	1.50	1.79	1.93	2.13	2.63	1.79	1.93	2.13	2.63	ns
DIFF_HSTL_II_18	0.97	1.09	1.22	1.49	1.69	1.83	2.03	2.51	1.69	1.83	2.03	2.51	ns
DIFF_HSTL_III_18	0.97	1.09	1.22	1.50	1.69	1.83	2.03	2.53	1.69	1.83	2.03	2.53	ns
DIFF_SSTL3_I	1.18	1.30	1.43	1.68	1.81	1.95	2.15	2.64	1.81	1.95	2.15	2.64	ns
DIFF_SSTL3_II	1.19	1.31	1.44	1.68	1.80	1.94	2.14	2.63	1.80	1.94	2.14	2.63	ns
DIFF_SSTL2_I	1.02	1.14	1.27	1.57	1.80	1.94	2.14	2.62	1.80	1.94	2.14	2.62	ns
DIFF_SSTL2_II	1.02	1.14	1.27	1.57	1.76	1.90	2.10	2.57	1.76	1.90	2.10	2.57	ns
DIFF_SSTL18_I	0.97	1.09	1.22	1.51	1.72	1.86	2.06	2.56	1.72	1.86	2.06	2.56	ns
DIFF_SSTL18_II	0.98	1.10	1.23	1.50	1.68	1.82	2.02	2.52	1.68	1.82	2.02	2.52	ns
DIFF_SSTL15_II	0.94	1.06	1.19	1.46	1.67	1.81	2.01	2.50	1.67	1.81	2.01	2.50	ns
DIFF_MOBILE_DDR	0.97	1.09	1.22	1.51	1.75	1.89	2.09	2.57	1.75	1.89	2.09	2.57	ns

Table 28: IOB Switching Characteristics for the Commercial (XC) Spartan-6 Devices (Cont'd)

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	-3	-3N	-2	-1L ⁽¹⁾	-3	-3N	-2	-1L ⁽¹⁾	-3	-3N	-2	-1L ⁽¹⁾	
LVC MOS33, Fast, 8 mA	1.34	1.46	1.59	1.82	2.07	2.21	2.41	3.03	2.07	2.21	2.41	3.03	ns
LVC MOS33, Fast, 12 mA	1.34	1.46	1.59	1.82	1.65	1.79	1.99	2.62	1.65	1.79	1.99	2.62	ns
LVC MOS33, Fast, 16 mA	1.34	1.46	1.59	1.82	1.65	1.79	1.99	2.62	1.65	1.79	1.99	2.62	ns
LVC MOS33, Fast, 24 mA	1.34	1.46	1.59	1.82	1.65	1.79	1.99	2.62	1.65	1.79	1.99	2.62	ns
LVC MOS25, QUIETIO, 2 mA	0.82	0.94	1.07	1.31	4.81	4.95	5.15	5.79	4.81	4.95	5.15	5.79	ns
LVC MOS25, QUIETIO, 4 mA	0.82	0.94	1.07	1.31	3.70	3.84	4.04	4.66	3.70	3.84	4.04	4.66	ns
LVC MOS25, QUIETIO, 6 mA	0.82	0.94	1.07	1.31	3.46	3.60	3.80	4.38	3.46	3.60	3.80	4.38	ns
LVC MOS25, QUIETIO, 8 mA	0.82	0.94	1.07	1.31	3.20	3.34	3.54	4.12	3.20	3.34	3.54	4.12	ns
LVC MOS25, QUIETIO, 12 mA	0.82	0.94	1.07	1.31	2.83	2.97	3.17	3.75	2.83	2.97	3.17	3.75	ns
LVC MOS25, QUIETIO, 16 mA	0.82	0.94	1.07	1.31	2.64	2.78	2.98	3.64	2.64	2.78	2.98	3.64	ns
LVC MOS25, QUIETIO, 24 mA	0.82	0.94	1.07	1.31	2.45	2.59	2.79	3.42	2.45	2.59	2.79	3.42	ns
LVC MOS25, Slow, 2 mA	0.82	0.94	1.07	1.31	3.78	3.92	4.12	4.76	3.78	3.92	4.12	4.76	ns
LVC MOS25, Slow, 4 mA	0.82	0.94	1.07	1.31	2.79	2.93	3.13	3.73	2.79	2.93	3.13	3.73	ns
LVC MOS25, Slow, 6 mA	0.82	0.94	1.07	1.31	2.73	2.87	3.07	3.66	2.73	2.87	3.07	3.66	ns
LVC MOS25, Slow, 8 mA	0.82	0.94	1.07	1.31	2.48	2.62	2.82	3.42	2.48	2.62	2.82	3.42	ns
LVC MOS25, Slow, 12 mA	0.82	0.94	1.07	1.31	2.01	2.15	2.35	2.95	2.01	2.15	2.35	2.95	ns
LVC MOS25, Slow, 16 mA	0.82	0.94	1.07	1.31	2.01	2.15	2.35	2.95	2.01	2.15	2.35	2.95	ns
LVC MOS25, Slow, 24 mA	0.82	0.94	1.07	1.31	2.01	2.15	2.35	2.94	2.01	2.15	2.35	2.94	ns
LVC MOS25, Fast, 2 mA	0.82	0.94	1.07	1.31	3.35	3.49	3.69	4.31	3.35	3.49	3.69	4.31	ns
LVC MOS25, Fast, 4 mA	0.82	0.94	1.07	1.31	2.25	2.39	2.59	3.22	2.25	2.39	2.59	3.22	ns
LVC MOS25, Fast, 6 mA	0.82	0.94	1.07	1.31	2.09	2.23	2.43	3.05	2.09	2.23	2.43	3.05	ns
LVC MOS25, Fast, 8 mA	0.82	0.94	1.07	1.31	2.02	2.16	2.36	2.98	2.02	2.16	2.36	2.98	ns
LVC MOS25, Fast, 12 mA	0.82	0.94	1.07	1.31	1.56	1.70	1.90	2.52	1.56	1.70	1.90	2.52	ns
LVC MOS25, Fast, 16 mA	0.82	0.94	1.07	1.31	1.56	1.70	1.90	2.52	1.56	1.70	1.90	2.52	ns
LVC MOS25, Fast, 24 mA	0.82	0.94	1.07	1.31	1.56	1.70	1.90	2.52	1.56	1.70	1.90	2.52	ns
LVC MOS18, QUIETIO, 2 mA	1.18	1.30	1.43	2.04	5.92	6.06	6.26	6.80	5.92	6.06	6.26	6.80	ns
LVC MOS18, QUIETIO, 4 mA	1.18	1.30	1.43	2.04	4.74	4.88	5.08	5.63	4.74	4.88	5.08	5.63	ns
LVC MOS18, QUIETIO, 6 mA	1.18	1.30	1.43	2.04	4.05	4.19	4.39	4.96	4.05	4.19	4.39	4.96	ns
LVC MOS18, QUIETIO, 8 mA	1.18	1.30	1.43	2.04	3.71	3.85	4.05	4.63	3.71	3.85	4.05	4.63	ns
LVC MOS18, QUIETIO, 12 mA	1.18	1.30	1.43	2.04	3.35	3.49	3.69	4.27	3.35	3.49	3.69	4.27	ns
LVC MOS18, QUIETIO, 16 mA	1.18	1.30	1.43	2.04	3.20	3.34	3.54	4.14	3.20	3.34	3.54	4.14	ns
LVC MOS18, QUIETIO, 24 mA	1.18	1.30	1.43	2.04	2.96	3.10	3.30	3.98	2.96	3.10	3.30	3.98	ns
LVC MOS18, Slow, 2 mA	1.18	1.30	1.43	2.04	4.62	4.76	4.96	5.54	4.62	4.76	4.96	5.54	ns
LVC MOS18, Slow, 4 mA	1.18	1.30	1.43	2.04	3.69	3.83	4.03	4.60	3.69	3.83	4.03	4.60	ns
LVC MOS18, Slow, 6 mA	1.18	1.30	1.43	2.04	3.00	3.14	3.34	3.94	3.00	3.14	3.34	3.94	ns
LVC MOS18, Slow, 8 mA	1.18	1.30	1.43	2.04	2.19	2.33	2.53	3.17	2.19	2.33	2.53	3.17	ns
LVC MOS18, Slow, 12 mA	1.18	1.30	1.43	2.04	1.99	2.13	2.33	2.95	1.99	2.13	2.33	2.95	ns
LVC MOS18, Slow, 16 mA	1.18	1.30	1.43	2.04	1.99	2.13	2.33	2.95	1.99	2.13	2.33	2.95	ns

Table 28: IOB Switching Characteristics for the Commercial (XC) Spartan-6 Devices (Cont'd)

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	-3	-3N	-2	-1L ⁽¹⁾	-3	-3N	-2	-1L ⁽¹⁾	-3	-3N	-2	-1L ⁽¹⁾	
LVC MOS15, Slow, 8 mA	0.98	1.10	1.23	1.79	2.30	2.44	2.64	3.25	2.30	2.44	2.64	3.25	ns
LVC MOS15, Slow, 12 mA	0.98	1.10	1.23	1.79	2.03	2.17	2.37	2.99	2.03	2.17	2.37	2.99	ns
LVC MOS15, Slow, 16 mA	0.98	1.10	1.23	1.79	2.01	2.15	2.35	2.97	2.01	2.15	2.35	2.97	ns
LVC MOS15, Fast, 2 mA	0.98	1.10	1.23	1.79	3.29	3.43	3.63	4.24	3.29	3.43	3.63	4.24	ns
LVC MOS15, Fast, 4 mA	0.98	1.10	1.23	1.79	2.27	2.41	2.61	3.22	2.27	2.41	2.61	3.22	ns
LVC MOS15, Fast, 6 mA	0.98	1.10	1.23	1.79	1.78	1.92	2.12	2.74	1.78	1.92	2.12	2.74	ns
LVC MOS15, Fast, 8 mA	0.98	1.10	1.23	1.79	1.73	1.87	2.07	2.69	1.73	1.87	2.07	2.69	ns
LVC MOS15, Fast, 12 mA	0.98	1.10	1.23	1.79	1.73	1.87	2.07	2.64	1.73	1.87	2.07	2.64	ns
LVC MOS15, Fast, 16 mA	0.98	1.10	1.23	1.79	1.73	1.87	2.07	2.64	1.73	1.87	2.07	2.64	ns
LVC MOS15_JEDEC, QUIETIO, 2 mA	1.03	1.15	1.28	1.49	5.49	5.63	5.83	6.37	5.49	5.63	5.83	6.37	ns
LVC MOS15_JEDEC, QUIETIO, 4 mA	1.03	1.15	1.28	1.49	4.61	4.75	4.95	5.51	4.61	4.75	4.95	5.51	ns
LVC MOS15_JEDEC, QUIETIO, 6 mA	1.03	1.15	1.28	1.49	4.07	4.21	4.41	4.97	4.07	4.21	4.41	4.97	ns
LVC MOS15_JEDEC, QUIETIO, 8 mA	1.03	1.15	1.28	1.49	3.92	4.06	4.26	4.81	3.92	4.06	4.26	4.81	ns
LVC MOS15_JEDEC, QUIETIO, 12 mA	1.03	1.15	1.28	1.49	3.54	3.68	3.88	4.51	3.54	3.68	3.88	4.51	ns
LVC MOS15_JEDEC, QUIETIO, 16 mA	1.03	1.15	1.28	1.49	3.33	3.47	3.67	4.31	3.33	3.47	3.67	4.31	ns
LVC MOS15_JEDEC, Slow, 2 mA	1.03	1.15	1.28	1.49	4.18	4.32	4.52	5.13	4.18	4.32	4.52	5.13	ns
LVC MOS15_JEDEC, Slow, 4 mA	1.03	1.15	1.28	1.49	3.42	3.56	3.76	4.35	3.42	3.56	3.76	4.35	ns
LVC MOS15_JEDEC, Slow, 6 mA	1.03	1.15	1.28	1.49	2.29	2.43	2.63	3.25	2.29	2.43	2.63	3.25	ns
LVC MOS15_JEDEC, Slow, 8 mA	1.03	1.15	1.28	1.49	2.30	2.44	2.64	3.26	2.30	2.44	2.64	3.26	ns
LVC MOS15_JEDEC, Slow, 12 mA	1.03	1.15	1.28	1.49	2.01	2.15	2.35	2.97	2.01	2.15	2.35	2.97	ns
LVC MOS15_JEDEC, Slow, 16 mA	1.03	1.15	1.28	1.49	2.01	2.15	2.35	2.97	2.01	2.15	2.35	2.97	ns
LVC MOS15_JEDEC, Fast, 2 mA	1.03	1.15	1.28	1.49	3.28	3.42	3.62	4.22	3.28	3.42	3.62	4.22	ns
LVC MOS15_JEDEC, Fast, 4 mA	1.03	1.15	1.28	1.49	2.27	2.41	2.61	3.23	2.27	2.41	2.61	3.23	ns
LVC MOS15_JEDEC, Fast, 6 mA	1.03	1.15	1.28	1.49	1.78	1.92	2.12	2.74	1.78	1.92	2.12	2.74	ns
LVC MOS15_JEDEC, Fast, 8 mA	1.03	1.15	1.28	1.49	1.73	1.87	2.07	2.69	1.73	1.87	2.07	2.69	ns
LVC MOS15_JEDEC, Fast, 12 mA	1.03	1.15	1.28	1.49	1.73	1.87	2.07	2.63	1.73	1.87	2.07	2.63	ns
LVC MOS15_JEDEC, Fast, 16 mA	1.03	1.15	1.28	1.49	1.73	1.87	2.07	2.63	1.73	1.87	2.07	2.63	ns
LVC MOS12, QUIETIO, 2 mA	0.91	1.03	1.16	1.51	6.40	6.54	6.74	7.30	6.40	6.54	6.74	7.30	ns
LVC MOS12, QUIETIO, 4 mA	0.91	1.03	1.16	1.51	4.98	5.12	5.32	5.90	4.98	5.12	5.32	5.90	ns
LVC MOS12, QUIETIO, 6 mA	0.91	1.03	1.16	1.51	4.65	4.79	4.99	5.55	4.65	4.79	4.99	5.55	ns
LVC MOS12, QUIETIO, 8 mA	0.91	1.03	1.16	1.51	4.23	4.37	4.57	5.21	4.23	4.37	4.57	5.21	ns
LVC MOS12, QUIETIO, 12 mA	0.91	1.03	1.16	1.51	3.98	4.12	4.32	4.94	3.98	4.12	4.32	4.94	ns
LVC MOS12, Slow, 2 mA	0.91	1.03	1.16	1.51	4.98	5.12	5.32	5.91	4.98	5.12	5.32	5.91	ns
LVC MOS12, Slow, 4 mA	0.91	1.03	1.16	1.51	2.84	2.98	3.18	3.81	2.84	2.98	3.18	3.81	ns
LVC MOS12, Slow, 6 mA	0.91	1.03	1.16	1.51	2.77	2.91	3.11	3.72	2.77	2.91	3.11	3.72	ns
LVC MOS12, Slow, 8 mA	0.91	1.03	1.16	1.51	2.34	2.48	2.68	3.31	2.34	2.48	2.68	3.31	ns
LVC MOS12, Slow, 12 mA	0.91	1.03	1.16	1.51	2.08	2.22	2.42	3.06	2.08	2.22	2.42	3.06	ns

Table 29: IOB Switching Characteristics for the Automotive XA Spartan-6 and the Spartan-6Q Devices⁽¹⁾ (Cont'd)

I/O Standard	T _{IOPI}		T _{IOOP}		T _{IOTP}		Units
	Speed Grade		Speed Grade		Speed Grade		
	-3	-2	-3	-2	-3	-2	
DIFF_SSTL3_I	1.26	1.44	1.95	2.15	1.95	2.15	ns
DIFF_SSTL3_II	1.26	1.44	1.94	2.14	1.94	2.14	ns
DIFF_SSTL2_I	1.09	1.27	1.94	2.14	1.94	2.14	ns
DIFF_SSTL2_II	1.09	1.27	1.90	2.10	1.90	2.10	ns
DIFF_SSTL18_I	1.04	1.22	1.86	2.06	1.86	2.06	ns
DIFF_SSTL18_II	1.05	1.23	1.82	2.02	1.82	2.02	ns
DIFF_SSTL15_II	1.01	1.19	1.81	2.01	1.81	2.01	ns
DIFF_MOBILE_DDR	1.04	1.22	1.89	2.09	1.89	2.09	ns
LVTTL, QUIETIO, 2 mA	1.42	1.60	5.64	5.84	5.64	5.84	ns
LVTTL, QUIETIO, 4 mA	1.42	1.60	4.46	4.66	4.46	4.66	ns
LVTTL, QUIETIO, 6 mA	1.42	1.60	3.92	4.12	3.92	4.12	ns
LVTTL, QUIETIO, 8 mA	1.42	1.60	3.37	3.57	3.37	3.57	ns
LVTTL, QUIETIO, 12 mA	1.42	1.60	3.42	3.62	3.42	3.62	ns
LVTTL, QUIETIO, 16 mA	1.42	1.60	3.09	3.29	3.09	3.29	ns
LVTTL, QUIETIO, 24 mA	1.42	1.60	2.83	3.03	2.83	3.03	ns
LVTTL, Slow, 2 mA	1.42	1.60	4.58	4.78	4.58	4.78	ns
LVTTL, Slow, 4 mA	1.42	1.60	3.38	3.58	3.38	3.58	ns
LVTTL, Slow, 6 mA	1.42	1.60	2.95	3.15	2.95	3.15	ns
LVTTL, Slow, 8 mA	1.42	1.60	2.73	2.93	2.73	2.93	ns
LVTTL, Slow, 12 mA	1.42	1.60	2.72	2.92	2.72	2.92	ns
LVTTL, Slow, 16 mA	1.42	1.60	2.53	2.73	2.53	2.73	ns
LVTTL, Slow, 24 mA	1.42	1.60	2.42	2.62	2.42	2.62	ns
LVTTL, Fast, 2 mA	1.42	1.60	4.04	4.24	4.04	4.24	ns
LVTTL, Fast, 4 mA	1.42	1.60	2.66	2.86	2.66	2.86	ns
LVTTL, Fast, 6 mA	1.42	1.60	2.58	2.78	2.58	2.78	ns
LVTTL, Fast, 8 mA	1.42	1.60	2.46	2.66	2.46	2.66	ns
LVTTL, Fast, 12 mA	1.42	1.60	1.97	2.17	1.97	2.17	ns
LVTTL, Fast, 16 mA	1.42	1.60	1.97	2.17	1.97	2.17	ns
LVTTL, Fast, 24 mA	1.42	1.60	1.97	2.17	1.97	2.17	ns
LVC MOS33, QUIETIO, 2 mA	1.41	1.59	5.65	5.85	5.65	5.85	ns
LVC MOS33, QUIETIO, 4 mA	1.41	1.59	4.20	4.40	4.20	4.40	ns
LVC MOS33, QUIETIO, 6 mA	1.41	1.59	3.65	3.85	3.65	3.85	ns
LVC MOS33, QUIETIO, 8 mA	1.41	1.59	3.51	3.71	3.51	3.71	ns
LVC MOS33, QUIETIO, 12 mA	1.41	1.59	3.09	3.29	3.09	3.29	ns
LVC MOS33, QUIETIO, 16 mA	1.41	1.59	2.91	3.11	2.91	3.11	ns
LVC MOS33, QUIETIO, 24 mA	1.41	1.59	2.73	2.93	2.73	2.93	ns
LVC MOS33, Slow, 2 mA	1.41	1.59	4.59	4.79	4.59	4.79	ns
LVC MOS33, Slow, 4 mA	1.41	1.59	3.14	3.34	3.14	3.34	ns

Table 34: SSO Limit per V_{CCO}/GND Pair (Cont'd)

V _{CCO}	I/O Standard	Drive	Slew	SSO Limit per V _{CCO} /GND Pair			
				All TQG144, CPG196, CSG225, FT(G)256, and LX devices in CSG324		All CS(G)484, FG(G)484, FG(G)676, FG(G)900, and LXT devices in CSG324	
				Bank 0/2	Bank 1/3	Bank 0/2	Bank 1/3/4/5
1.5V	LVCMOS15, LVCMOS15_JEDEC	2	Fast	33	40	33	41
			Slow	57	62	57	56
			QuietIO	70	67	70	66
		4	Fast	19	21	19	21
			Slow	30	30	30	24
			QuietIO	38	33	38	30
		6	Fast	14	16	14	16
			Slow	18	19	18	17
			QuietIO	27	24	27	21
		8	Fast	11	13	11	12
			Slow	16	16	16	14
			QuietIO	23	20	23	17
		12	Fast	N/A	5	N/A	4
			Slow	N/A	8	N/A	5
			QuietIO	N/A	10	N/A	9
		16	Fast	N/A	5	N/A	4
			Slow	N/A	8	N/A	8
			QuietIO	N/A	10	N/A	9
	HSTL_I			9	10	9	10
	HSTL_II			N/A	5	N/A	6
	HSTL_III			7	9	7	9
	DIFF_HSTL_I			27	30	27	30
	DIFF_HSTL_II			N/A	15	N/A	18
	DIFF_HSTL_III			21	27	21	27
	SSTL_15_II ⁽³⁾			N/A	5	N/A	4
	DIFF_SSTL_15_II ⁽³⁾			N/A	15	N/A	12

Input Serializer/Deserializer Switching Characteristics

Table 37: ISERDES2 Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
Setup/Hold for Control Lines						
T _{ISCKC_BITS_{LIP}} / T _{ISCKC_BITS_{LIP}}	BITS _{LIP} pin Setup/Hold with respect to CLKDIV	0.16/ −0.09	0.20/ −0.09	0.31/ −0.09	0.34/ −0.14	ns
T _{ISCKC_CE} / T _{ISCKC_CE}	CE pin Setup/Hold with respect to CLK	0.71/ −0.47	0.71/ −0.42	0.97/ −0.42	1.39/ −0.71	ns
Setup/Hold for Data Lines						
T _{ISDCK_D} / T _{ISCKD_D}	D pin Setup/Hold with respect to CLK	0.24/ −0.15	0.25/ −0.05	0.29/ −0.05	0.09/ −0.05	ns
T _{ISDCK_DDLY} / T _{ISCKD_DDLY}	DDLY pin Setup/Hold with respect to CLK (using IODELAY2)	−0.25/ 0.30	−0.25/ 0.42	−0.25/ 0.56	−0.54/ 0.67	ns
T _{ISDCK_D_DDR} / T _{ISCKD_D_DDR}	D pin Setup/Hold with respect to CLK at DDR mode	−0.03/ 0.04	−0.03/ 0.16	−0.03/ 0.18	−0.05/ 0.12	ns
T _{ISDCK_DDLY_DDR} / T _{ISCKD_DDLY_DDR}	D pin Setup/Hold with respect to CLK at DDR mode (using IODELAY2)	−0.40/ 0.48	−0.40/ 0.53	−0.40/ 0.71	−0.71/ 0.86	ns
Sequential Delays						
T _{ISCKO_Q}	CLKDIV to out at Q pin	1.30	1.44	2.02	2.22	ns
F _{CLKDIV}	CLKDIV maximum frequency	270	262.5	250	125	MHz

Output Serializer/Deserializer Switching Characteristics

Table 38: OSERDES2 Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
Setup/Hold						
T _{OSDCK_D} /T _{OSCKD_D}	D input Setup/Hold with respect to CLKDIV	−0.03/ 1.02	−0.03/ 1.17	−0.03/ 1.27	−0.02/ 0.23	ns
T _{OSDCK_T} /T _{OSCKD_T} ⁽¹⁾	T input Setup/Hold with respect to CLK	−0.05/ 1.03	−0.05/ 1.13	−0.05/ 1.23	−0.05/ 0.24	ns
T _{OSCCK_OCE} /T _{OSCKC_OCE}	OCE input Setup/Hold with respect to CLK	0.12/ −0.03	0.15/ −0.03	0.24/ −0.03	0.28/ −0.17	ns
T _{OSCCK_TCE} /T _{OSCKC_TCE}	TCE input Setup/Hold with respect to CLK	0.14/ −0.08	0.17/ −0.08	0.27/ −0.08	0.31/ −0.16	ns
Sequential Delays						
T _{OSCKO_OQ}	Clock to out from CLK to OQ	0.94	1.11	1.51	1.89	ns
T _{OSCKO_TQ}	Clock to out from CLK to TQ	0.94	1.11	1.51	1.91	ns
F _{CLKDIV}	CLKDIV maximum frequency	270	262.5	250	125	MHz

Notes:

- $T_{OSDCK_T2} / T_{OSCKD_T2}$ (T input setup/hold with respect to CLKDIV) are reported as $T_{OSDCK_T} / T_{OSCKD_T}$ in TRACE report.

CLB Switching Characteristics (SLICEM Only)

Table 40: CLB Switching Characteristics (SLICEM Only)

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
Combinatorial Delays						
T _{ILO}	An – Dn LUT inputs to A to D outputs	0.21	0.26	0.26	0.46	ns, Max
	An – Dn LUT inputs through F7AMUX/F7BMUX to AMUX/CMUX output	0.37	0.43	0.43	0.77	ns, Max
T _{OPAB}	An – Dn LUT inputs through F7AMUX or F7BMUX and F8MUX to BMUX output	0.37	0.46	0.46	0.84	ns, Max
T _{ITO}	An – Dn LUT inputs through latch to AQ – DQ outputs	0.82	0.95	0.95	1.64	ns, Max
T _{TITO_LOGIC}	An – Dn LUT inputs to AQ – DQ outputs (latch as logic)	0.82	0.95	0.95	1.64	ns, Max
T _{OPCYA}	An LUT inputs to COUT output	0.38	0.48	0.48	0.69	ns, Max
T _{OPCYB}	Bn LUT inputs to COUT output	0.38	0.49	0.49	0.71	ns, Max
T _{OPCYC}	Cn LUT inputs to COUT output	0.28	0.33	0.33	0.55	ns, Max
T _{OPCYD}	Dn LUT inputs to COUT output	0.28	0.35	0.35	0.52	ns, Max
T _{AXCY}	AX input to COUT output	0.21	0.26	0.26	0.36	ns, Max
T _{BXCY}	BX input to COUT output	0.13	0.16	0.16	0.18	ns, Max
T _{CXCY}	CX input to COUT output	0.10	0.12	0.12	0.09	ns, Max
T _{DXCY}	DX input to COUT output	0.09	0.11	0.11	0.09	ns, Max
T _{BYP}	CIN input to COUT output	0.08	0.10	0.10	0.06	ns, Max
T _{CINA}	CIN input to AMUX output	0.21	0.22	0.22	0.47	ns, Max
T _{CINB}	CIN input to BMUX output	0.30	0.31	0.31	0.57	ns, Max
T _{CINC}	CIN input to CMUX output	0.29	0.31	0.31	0.58	ns, Max
T _{CIND}	CIN input to DMUX output	0.31	0.32	0.32	0.68	ns, Max
Sequential Delays						
T _{CKO}	Clock to AQ – DQ outputs	0.45	0.53	0.53	0.74	ns, Max
Setup and Hold Times of CLB Flip-Flops Before/After Clock CLK						
T _{DICK} /T _{CKDI}	AX – DX input to CLK on A – D flip-flops	0.42/ 0.28	0.47/ 0.39	0.47/ 0.39	0.90/ 0.56	ns, Min
T _{CECK} /T _{CKCE}	CE input to CLK on A – D flip-flops	0.31/ –0.07	0.37/ –0.07	0.37/ –0.07	0.59/ –0.27	ns, Min
T _{SRCK} /T _{CKSR}	SR input to CLK on A – D flip-flops for XC devices	0.41/ 0.02	0.42/ 0.02	0.42/ 0.02	0.68/ –0.29	ns, Min
	SR input to CLK on A – D flip-flops for XA and XQ devices	0.41/ 0.02	N/A	0.44/ 0.02	0.68/ –0.29	ns, Min
T _{CINCK} /T _{CKCIN}	CIN input to CLK on A – D flip-flops	0.31/ –0.17	0.31/ –0.13	0.31/ –0.13	0.81/ –0.42	ns, Min
Set/Reset						
T _{RPW}	SR input minimum pulse width	0.41	0.48	0.48	1.37	ns, Min
T _{RQ}	Delay from SR input to AQ – DQ flip-flops	0.60	0.70	0.70	0.88	ns, Max
T _{CEO}	Delay from CE input to AQ – DQ flip-flops	0.60	0.65	0.65	0.90	ns, Max
F _{TOG}	Toggle frequency (for export control)	862	806	667	500	MHz

CLB Distributed RAM Switching Characteristics (SLICEM Only)

Table 41: CLB Distributed RAM Switching Characteristics (SLICEM Only)

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
Sequential Delays						
T _{SHCKO}	Clock to A – D outputs	1.26	1.55	1.55	2.35	ns, Max
	Clock to A – D outputs (direct output path)	0.96	1.20	1.20	1.87	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{DS} /T _{DH}	AX – DX or AI – DI inputs to CLK	0.59/ 0.17	0.73/ 0.22	0.73/ 0.22	1.17/ 0.33	ns, Min
T _{AS} /T _{AH}	Address An inputs to clock for XC devices	0.28/ 0.35	0.32/ 0.42	0.32/ 0.42	0.26/ 0.71	ns, Min
	Address An inputs to clock for XA and XQ devices	0.28/ 0.51	N/A	0.32/ 0.51	0.26/ 0.71	ns, Min
T _{WS} /T _{WH}	WE input to clock	0.31/ –0.08	0.37/ –0.08	0.37/ –0.08	0.59/ –0.27	ns, Min
T _{CECK} /T _{CKCE}	CE input to CLK	0.31/ –0.08	0.37/ –0.08	0.37/ –0.08	0.59/ –0.27	ns, Min

CLB Shift Register Switching Characteristics (SLICEM Only)

Table 42: CLB Shift Register Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
Sequential Delays						
T _{REG}	Clock to A – D outputs	1.35	1.78	1.78	2.74	ns, Max
	Clock to A – D outputs (direct output path)	1.24	1.65	1.65	2.48	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{WS} /T _{WH}	WE input to CLK	0.20/ –0.07	0.24/ –0.07	0.24/ –0.07	0.29/ –0.27	ns, Min
T _{CECK} /T _{CKCE}	CE input to CLK for XC devices	0.30/ 0.30	0.30/ 0.38	0.30/ 0.38	0.82/ –0.41	ns, Min
	CE input to CLK for XA and XQ devices	0.32/ 0.30	N/A	0.40/ 0.38	0.82/ –0.41	ns, Min
T _{DS} /T _{DH}	AX – DX or AI – DI inputs to CLK	0.07/ 0.11	0.09/ 0.14	0.09/ 0.14	0.11/ 0.23	ns, Min

Clock Buffers and Networks

Table 48: Global Clock Switching Characteristics (BUFGMUX)

Symbol	Description	Devices	Speed Grade				Units
			-3	-3N	-2	-1L	
T _{GSI}	S pin Setup to I0/I1 inputs	LX devices	0.25	0.31	0.48	0.48	ns
		LXT devices	0.25	0.31	0.48	N/A	ns
T _{GIO}	BUFGMUX delay from I0/I1 to O	LX devices	0.21	0.21	0.21	0.21	ns
		LXT devices	0.21	0.21	0.21	N/A	ns
Maximum Frequency							
F _{MAX}	Global clock tree (BUFGMUX)	LX devices	400	400	375	250	MHz
		LXT devices	400	400	375	N/A	MHz

Table 49: Input/Output Clock Switching Characteristics (BUFIO2)

Symbol	Description	Devices	Speed Grade				Units
			-3	-3N	-2	-1L	
T _{BUFCO_O}	Clock to out delay from I to O	LX devices	0.67	0.82	1.09	1.50	ns
		LXT devices	0.67	0.82	1.09	N/A	ns
Maximum Frequency							
F _{MAX}	I/O clock tree (BUFIO2)	LX devices	540	525	500	300	MHz
		LXT devices	540	525	500	N/A	MHz

Table 50: Input/Output Clock Switching Characteristics (BUFIO2FB)

Symbol	Description	Devices	Speed Grade				Units
			-3	-3N	-2	-1L	
Maximum Frequency							
F _{MAX}	I/O clock tree (BUFIO2FB)	LX devices	1080	1050	950	500	MHz
		LXT devices	1080	1050	950	N/A	MHz

Table 51: Input/Output Clock Switching Characteristics (BUFPLL)

Symbol	Description	Devices	Speed Grade				Units
			-3	-3N	-2	-1L	
Maximum Frequency							
F _{MAX}	BUFPLL clock tree (BUFPLL)	LX devices	1080	1050	950	500	MHz
		LXT devices	1080	1050	950	N/A	MHz

PLL Switching Characteristics

Table 52: PLL Specification

Symbol	Description	Device ⁽¹⁾	Speed Grade				Units
			-3	-3N	-2	-1L	
F_{INMAX}	Maximum Input Clock Frequency from I/O Clock	LX devices	540	525	450	300	MHz
		LXT devices	540	525	450	N/A	MHz
	Maximum Input Clock Frequency from Global Clock	LX devices	400	400	375	250	MHz
		LXT devices	400	400	375	N/A	MHz

DCM Switching Characteristics

Table 53: Operating Frequency Ranges and Conditions for the Delay-Locked Loop (DLL)⁽¹⁾

Symbol	Description	Speed Grade								Units	
		-3		-3N		-2		-1L			
		Min	Max	Min	Max	Min	Max	Min	Max		
Input Frequency Ranges											
CLKIN_FREQ_DLL	Frequency of the CLKIN clock input when the CLKDV output is not used.	5 ⁽²⁾	280 ⁽³⁾	5 ⁽²⁾	280 ⁽³⁾	5 ⁽²⁾	250 ⁽³⁾	5 ⁽²⁾	175 ⁽³⁾	MHz	
	Frequency of the CLKIN clock input when using the CLKDV output.	5 ⁽²⁾	280 ⁽³⁾	5 ⁽²⁾	280 ⁽³⁾	5 ⁽²⁾	250 ⁽³⁾	5 ⁽²⁾	133 ⁽³⁾	MHz	
Input Pulse Requirements											
CLKIN_PULSE	CLKIN pulse width as a percentage of the CLKIN period for CLKIN_FREQ_DLL < 150 MHz	40	60	40	60	40	60	40	60	%	
	CLKIN pulse width as a percentage of the CLKIN period for CLKIN_FREQ_DLL > 150 MHz	45	55	45	55	45	55	45	55	%	
Input Clock Jitter Tolerance and Delay Path Variation ⁽⁴⁾											
CLKIN_CYC_JITT_DLL_LF	Cycle-to-cycle jitter at the CLKIN input for CLKIN_FREQ_DLL < 150 MHz	–	±300	–	±300	–	±300	–	±300	ps	
CLKIN_CYC_JITT_DLL_HF	Cycle-to-cycle jitter at the CLKIN input for CLKIN_FREQ_DLL > 150 MHz.	–	±150	–	±150	–	±150	–	±150	ps	
CLKIN_PER_JITT_DLL	Period jitter at the CLKIN input.	–	±1	–	±1	–	±1	–	±1	ns	
CLKFB_DELAY_VAR_EXT	Allowable variation of the off-chip feedback delay from the DCM output to the CLKFB input.	–	±1	–	±1	–	±1	–	±1	ns	

Notes:

- DLL specifications apply when using any of the DLL outputs: CLK0, CLK90, CLK180, CLK270, CLK2X, CLK2X180, or CLKDV.
- When operating independently of the DLL, the DFS supports lower CLKIN_FREQ_DLL frequencies. See Table 55.
- The CLKIN_DIVIDE_BY_2 attribute increases the effective input frequency range. When set to TRUE, the input clock frequency is divided by two as it enters the DCM. Input clock frequencies for the clock buffer being used can be increased up to the F_{MAX} (see Table 48 and Table 49 for BUFG and BUFGIO2 limits). When used with CLK_FEEDBACK=2X, the input clock frequency matches the frequency for CLK2X, and is limited to CLKOUT_FREQ_2X.
- CLKIN_FREQ_DLL input jitter beyond these limits can cause the DCM to lose LOCK, indicated by the LOCKED output deasserting. The user must then reset the DCM.
- When using both DCMs in a CMT, both DCMs must be LOCKED.

Table 54: Switching Characteristics for the Delay-Locked Loop (DLL)⁽¹⁾ (Cont'd)

Symbol	Description	Speed Grade								Units
		-3		-3N		-2		-1L		
		Min	Max	Min	Max	Min	Max	Min	Max	
LOCK_DLL ⁽³⁾	When using the DLL alone: The time from deassertion at the DCM's reset input to the rising transition at its LOCKED output. When the DCM is locked, the CLKIN and CLKFB signals are in phase. CLKIN_FREQ_DLL < 50 MHz.	–	5	–	5	–	5	–	5	ms
	When using the DLL alone: The time from deassertion at the DCM's reset input to the rising transition at its LOCKED output. When the DCM is locked, the CLKIN and CLKFB signals are in phase. CLKIN_FREQ_DLL > 50 MHz	–	0.60	–	0.60	–	0.60	–	0.60	ms
Delay Lines										
DCM_DELAY_STEP ⁽⁵⁾	Finest delay resolution, averaged over all steps.	10	40	10	40	10	40	10	40	ps

Notes:

1. The values in this table are based on the operating conditions described in Table 2 and Table 53.
2. Indicates the maximum amount of output jitter that the DCM adds to the jitter on the CLKIN input.
3. For optimal jitter tolerance and faster LOCK time, use the CLKIN_PERIOD attribute.
4. Some jitter and duty-cycle specifications include 1% of input clock period or 0.01 UI. For example, this data sheet specifies a maximum jitter of $\pm(1\% \text{ of CLKIN period} + 150 \text{ ps})$. Assuming that the CLKIN frequency is 100 MHz, the equivalent CLKIN period is 10 ns. Since 1% of 10 ns is 0.1 ns or 100 ps, the maximum jitter is $\pm(100 \text{ ps} + 150 \text{ ps}) = \pm 250 \text{ ps}$.
5. A typical delay step size is 23 ps.
6. The timing analysis tools use the CLK_FEEDBACK = 1X condition for the CLKIN_CLKFB_PHASE value (reported as phase error). When using CLK_FEEDBACK = 2X, add 100 ps to the phase error for the CLKIN_CLKFB_PHASE value (as shown in this table).

Table 55: Recommended Operating Conditions for the Digital Frequency Synthesizer (DFS)⁽¹⁾

Symbol	Description	Speed Grade								Units
		-3		-3N		-2		-1L		
		Min	Max	Min	Max	Min	Max	Min	Max	
Input Frequency Ranges ⁽²⁾										
CLKIN_FREQ_FX	Frequency for the CLKIN input. Also described as F _{CLKIN} .	0.5	375 ⁽³⁾	0.5	375 ⁽³⁾	0.5	333 ⁽³⁾	0.5	200 ⁽³⁾	MHz
Input Clock Jitter Tolerance ⁽⁴⁾										
CLKIN_CYC_JITT_FX_LF	Cycle-to-cycle jitter at the CLKIN input, based on CLKFX output frequency: FCLKFX < 150 MHz.	–	±300	–	±300	–	±300	–	±300	ps
CLKIN_CYC_JITT_FX_HF	Cycle-to-cycle jitter at the CLKIN input, based on CLKFX output frequency: FCLKFX > 150 MHz.	–	±150	–	±150	–	±150	–	±150	ps
CLKIN_PER_JITT_FX	Period jitter at the CLKIN input.	–	±1	–	±1	–	±1	–	±1	ns

Notes:

1. DFS specifications apply when using either of the DFS outputs (CLKFX or CLKFX180).
2. When using both DFS and DLL outputs on the same DCM, follow the more restrictive CLKIN_FREQ_DLL specifications in Table 53.
3. The CLKIN_DIVIDE_BY_2 attribute increases the effective input frequency range. When set to TRUE, the input clock frequency is divided by two as it enters the DCM. Input clock frequencies for the clock buffer being used can be increased up to the F_{MAX} (see Table 48 and Table 49 for BUFG and BUFGIO limits).
4. CLKIN input jitter beyond these limits can cause the DCM to lose LOCK.

Table 59: Switching Characteristics for the Phase-Shift Clock in Variable Phase Mode⁽¹⁾

Symbol	Description	Amount of Phase Shift	Units
Phase Shifting Range			
MAX_STEPS ⁽²⁾	When CLKIN < 60 MHz, the maximum allowed number of DCM_DELAY_STEP steps for a given CLKIN clock period, where T = CLKIN clock period in ns. When using CLKIN_DIVIDE_BY_2 = TRUE, double the clock-effective clock period.	$\pm(\text{INTEGER}(10 \times (\text{TCLKIN} - 3 \text{ ns})))$	steps
	When CLKIN ≥ 60 MHz, the maximum allowed number of DCM_DELAY_STEP steps for a given CLKIN clock period, where T = CLKIN clock period in ns. When using CLKIN_DIVIDE_BY_2 = TRUE, double the clock-effective clock period.	$\pm(\text{INTEGER}(15 \times (\text{TCLKIN} - 3 \text{ ns})))$	steps
FINE_SHIFT_RANGE_MIN	Minimum guaranteed delay for variable phase shifting.	$\pm(\text{MAX_STEPS} \times \text{DCM_DELAY_STEP_MIN})$	ps
FINE_SHIFT_RANGE_MAX	Maximum guaranteed delay for variable phase shifting	$\pm(\text{MAX_STEPS} \times \text{DCM_DELAY_STEP_MAX})$	ps

Notes:

- The values in this table are based on the operating conditions described in Table 53 and Table 58.
- The maximum variable phase shift range, MAX_STEPS, is only valid when the DCM has no initial fixed-phase shifting, that is, the PHASE_SHIFT attribute is set to 0.
- The DCM_DELAY_STEP values are provided at the end of Table 54.

Table 60: Miscellaneous DCM Timing Parameters⁽¹⁾

Symbol	Description	Min	Max	Units
DCM_RST_PW_MIN	Minimum duration of a RST pulse width	3	–	CLKIN cycles

Notes:

- This limit only applies to applications that use the DCM DLL outputs (CLK0, CLK90, CLK180, CLK270, CLK2X, CLK2X180, and CLKDV). The DCM DFS outputs (CLKFX, CLKFXDV, CLKFX180) are unaffected.

Table 61: Frequency Synthesis

Attribute	Min	Max
CLKFX_MULTIPLY (DCM_SP)	2	32
CLKFX_DIVIDE (DCM_SP)	1	32
CLKDV_DIVIDE (DCM_SP)	1.5	16
CLKFX_MULTIPLY (DCM_CLKGEN)	2	256
CLKFX_DIVIDE (DCM_CLKGEN)	1	256
CLKFXDV_DIVIDE (DCM_CLKGEN)	2	32

Table 62: DCM Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
T _{DMCK_PSEN} /T _{DMCKC_PSEN}	PSEN Setup/Hold	1.50/ 0.00	1.50/ 0.00	1.50/ 0.00	1.50/ 0.00	ns
T _{DMCK_PSINCDEC} /T _{DMCKC_PSINCDEC}	PSINCDEC Setup/Hold	1.50/ 0.00	1.50/ 0.00	1.50/ 0.00	1.50/ 0.00	ns
T _{DMCKO_PSDONE}	Clock to out of PSDONE	1.50	1.50	1.50	1.50	ns

Table 68: Global Clock Input to Output Delay With DCM and PLL in System-Synchronous Mode

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
LVCMOS25 Global Clock Input to Output Delay using Output Flip-Flop, 12mA, Fast Slew Rate, <i>with</i> DCM in System-Synchronous Mode and PLL in DCM2PLL Mode.							
T _{ICKOFDCM_PLL}	Global Clock and OUTFF with DCM and PLL	XC6SLX4	4.78	N/A	6.32	7.09	ns
		XC6SLX9	4.78	5.24	6.32	7.09	ns
		XC6SLX16	4.70	5.12	5.94	6.63	ns
		XC6SLX25	4.70	5.09	5.92	7.30	ns
		XC6SLX25T	4.70	5.09	5.92	N/A	ns
		XC6SLX45	4.63	4.98	5.83	7.26	ns
		XC6SLX45T	4.63	4.98	5.83	N/A	ns
		XC6SLX75	4.68	5.04	5.88	6.90	ns
		XC6SLX75T	4.68	5.04	5.88	N/A	ns
		XC6SLX100	4.72	5.07	5.92	7.77	ns
		XC6SLX100T	4.76	5.07	5.92	N/A	ns
		XC6SLX150	4.44	4.73	5.31	6.96	ns
		XC6SLX150T	4.44	4.73	5.31	N/A	ns
		XA6SLX4	5.07	N/A	6.18	N/A	ns
		XA6SLX9	5.07	N/A	6.18	N/A	ns
		XA6SLX16	5.22	N/A	5.77	N/A	ns
		XA6SLX25	5.01	N/A	5.80	N/A	ns
		XA6SLX25T	5.01	N/A	5.90	N/A	ns
		XA6SLX45	4.93	N/A	5.67	N/A	ns
		XA6SLX45T	4.93	N/A	5.67	N/A	ns
		XA6SLX75	4.94	N/A	5.70	N/A	ns
		XA6SLX75T	4.94	N/A	5.70	N/A	ns
		XA6SLX100	N/A	N/A	5.77	N/A	ns
		XQ6SLX75	N/A	N/A	5.70	6.90	ns
		XQ6SLX75T	4.94	N/A	5.70	N/A	ns
		XQ6SLX150	N/A	N/A	5.31	6.96	ns
		XQ6SLX150T	5.02	N/A	5.31	N/A	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. DCM and PLL output jitter are already included in the timing calculation.

Spartan-6 Device Pin-to-Pin Input Parameter Guidelines

All devices are 100% functionally tested. The representative values for typical pin locations and normal clock loading are listed in Table 70 through Table 77. Values are expressed in nanoseconds unless otherwise noted.

Table 70: Global Clock Setup and Hold Without DCM or PLL (No Delay)

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
Input Setup and Hold Time Relative to Global Clock Input Signal for LVC MOS25 Standard.(1)							
T _{PSND} / T _{PHND}	No Delay Global Clock and IFF(3) without DCM or PLL	XC6SLX4	0.10/1.56	N/A	0.10/1.83	0.07/2.54	ns
		XC6SLX9	0.10/1.56	0.10/1.57	0.10/1.84	0.07/2.54	ns
		XC6SLX16	0.12/1.42	0.12/1.48	0.12/1.64	0.13/2.19	ns
		XC6SLX25	0.18/1.64	0.18/1.75	0.18/1.99	0.11/2.57	ns
		XC6SLX25T	0.18/1.64	0.18/1.75	0.18/1.99	N/A	ns
		XC6SLX45	−0.08/1.80	−0.08/1.95	−0.08/2.27	−0.17/2.74	ns
		XC6SLX45T	−0.08/1.80	−0.08/1.95	−0.08/2.27	N/A	ns
		XC6SLX75	0.13/1.81	0.13/2.06	0.13/2.27	−0.12/3.30	ns
		XC6SLX75T	0.13/1.81	0.13/2.06	0.13/2.27	N/A	ns
		XC6SLX100	−0.14/2.03	−0.14/2.24	−0.14/2.56	−0.17/3.44	ns
		XC6SLX100T	−0.14/2.03	−0.14/2.24	−0.14/2.56	N/A	ns
		XC6SLX150	−0.24/2.42	−0.24/2.74	−0.24/2.95	−0.60/3.75	ns
		XC6SLX150T	−0.24/2.42	−0.24/2.74	−0.24/2.95	N/A	ns
		XA6SLX4	0.10/1.57	N/A	0.10/1.84	N/A	ns
		XA6SLX9	0.10/1.57	N/A	0.10/1.84	N/A	ns
		XA6SLX16	0.12/1.43	N/A	0.12/1.64	N/A	ns
		XA6SLX25	0.18/1.65	N/A	0.18/1.99	N/A	ns
		XA6SLX25T	0.18/1.65	N/A	0.18/1.99	N/A	ns
		XA6SLX45	−0.08/1.82	N/A	−0.08/2.27	N/A	ns
		XA6SLX45T	−0.08/1.82	N/A	−0.08/2.27	N/A	ns
		XA6SLX75	0.13/2.02	N/A	0.13/2.32	N/A	ns
		XA6SLX75T	0.13/2.02	N/A	0.13/2.32	N/A	ns
		XA6SLX100	N/A	N/A	0.10/2.51	N/A	ns
		XQ6SLX75	N/A	N/A	0.13/2.32	−0.12/3.30	ns
		XQ6SLX75T	0.13/2.02	N/A	0.13/2.32	N/A	ns
		XQ6SLX150	N/A	N/A	−0.24/2.95	−0.60/3.75	ns
		XQ6SLX150T	−0.24/2.74	N/A	−0.24/2.95	N/A	ns

Notes:

- Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
- IFF = Input Flip-Flop or Latch.

Table 71: Global Clock Setup and Hold Without DCM or PLL (Default Delay)

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
Input Setup and Hold Time Relative to Global Clock Input Signal for LVCMOS25 Standard. ⁽¹⁾							
T _{PSFD} / T _{PHFD}	Default Delay ⁽²⁾ Global Clock and IFF ⁽³⁾ without DCM or PLL	XC6SLX4	0.66/1.17	N/A	1.05/0.79	2.09/1.05	ns
		XC6SLX9	0.66/1.17	0.75/1.17	1.05/1.17	2.09/1.05	ns
		XC6SLX16	0.87/1.16	0.93/1.16	0.96/1.16	1.86/1.06	ns
		XC6SLX25	0.68/0.77	0.81/0.81	0.87/0.82	2.21/1.33	ns
		XC6SLX25T	0.68/0.77	0.81/0.81	0.87/0.82	N/A	ns
		XC6SLX45	0.40/1.05	0.42/1.17	0.64/1.20	1.61/1.67	ns
		XC6SLX45T	0.40/1.05	0.42/1.17	0.64/1.20	N/A	ns
		XC6SLX75	0.41/1.11	0.41/1.13	0.80/1.14	1.23/1.82	ns
		XC6SLX75T	0.41/1.11	0.41/1.13	0.80/1.14	N/A	ns
		XC6SLX100	0.39/1.12	0.39/1.23	0.39/1.28	1.13/1.94	ns
		XC6SLX100T	0.39/1.12	0.39/1.23	0.39/1.28	N/A	ns
		XC6SLX150	0.23/1.54	0.23/1.62	0.23/1.62	1.14/2.05	ns
		XC6SLX150T	0.23/1.54	0.23/1.62	0.23/1.62	N/A	ns
		XA6SLX4	0.73/1.18	N/A	1.05/0.80	N/A	ns
		XA6SLX9	0.73/1.18	N/A	1.05/0.80	N/A	ns
		XA6SLX16	0.90/1.20	N/A	0.96/0.75	N/A	ns
		XA6SLX25	0.70/0.81	N/A	0.87/0.91	N/A	ns
		XA6SLX25T	0.76/0.81	N/A	1.03/0.91	N/A	ns
		XA6SLX45	0.40/1.06	N/A	0.64/1.20	N/A	ns
		XA6SLX45T	0.40/1.06	N/A	0.64/1.20	N/A	ns
		XA6SLX75	0.41/1.24	N/A	0.80/1.18	N/A	ns
		XA6SLX75T	0.41/1.24	N/A	0.80/1.18	N/A	ns
		XA6SLX100	N/A	N/A	0.86/1.55	N/A	ns
		XQ6SLX75	N/A	N/A	0.80/1.18	1.23/1.82	ns
		XQ6SLX75T	0.41/1.24	N/A	0.80/1.18	N/A	ns
		XQ6SLX150	N/A	N/A	0.28/1.57	1.14/2.05	ns
		XQ6SLX150T	0.28/1.78	N/A	0.28/1.57	N/A	ns

Notes:

- Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
- Default delay uses IODELAY2 tap 0.
- IFF = Input Flip-Flop or Latch.

Date	Version	Description of Revisions
06/14/10	1.5	In Table 2, added note 5 and added temperature range to V_{FS} and R_{FUSE}. Removed speed grade delineation, revised I_{RPD} description, and updated note 2 in Table 4. Added note 2 to Table 7. Added $DIFF_MOBILE_DDR$ to Table 8 and Table 10. Added note 4 to Table 15. Changed minimum DV_{PPIN} in Table 16. Updated $F_{GTPDRCLK}$ in Table 19. Increased maximum T_{LLSKEW} in Table 22. Updated descriptions and added data to Table 23. Removed note 1 and added new data to the Networking Applications section in Table 25. Updated Table 26 and Table 27 to the data in ISE v12.1 software with speed specification v1.08. In Table 28, added $DIFF_MOBILE_DDR$ and updated -4 speed grade data. Updated the maximum I/O pairs per bank in Table 33. Updated note 2 on Table 39. Revised the F_{MAX} in Table 44. In Table 47, updated description for $T_{SMCKCSO}$, revised values for T_{POR} and added Min value, added $T_{BPIICCK}$ and $T_{SPIICCK}$. Also in Table 47, added device dependencies to F_{SMCKCK} and F_{RBCKCK}. Updated and added data to Table 63 through Table 78, and Table 81. In Table 79, added data on the XC6SLX45-FG(G)676 and revised the XC6SLX45T and XC6SLX150T values. The following changes to this specification are addressed in the product change notice XC6SLX45-FG(G)676, <i>MCB Performance and JTAG Revision Code for Spartan-6 LX16 and LX45 FPGAs</i>. In Table 2, revised the V_{CCINT} to add the memory controller block extended performance specifications. In Table 25, changed the standard specifications and added extended performance specifications for the memory controller block and note 2. Added note 4 and updated values in Table 34.
06/24/10	1.6	Production release of XC6SLX45T (-2 and -3 speed grades), XC6SLX16 and XC6SLX45 (-3 speed grade) devices which includes changes to Table 26 and Table 27 (ISE v12.1 software with speed specification v1.08). Added the -3N speed grade, which designates Spartan-6 devices that do not support MCB functionality. This includes changes to Table 2 (note 2), Table 25 (note 4), and Switching Characteristics (Table 26). Updated Simultaneously Switching Outputs discussion. Added -3 speed grade values for T_{TAP} and F_{MINCAL} values in Table 39. In Table 40, updated T_{RPW} (-2 and -3 speed grade) values and F_{TOG} (-3 speed grade) values. In Table 48, updated T_{GIO} (-2 and -3 speed grade) values. Updated -3 values in spread spectrum section of Table 57.
07/16/10	1.7	Production release of specific devices listed in Table 26 and Table 27 using ISE v12.2 software with speed specification v1.11. Added note 4 advising designers of the patch which contains v1.11. Also updated the -1L speed specification to v1.04. Updated numerous -4 and -1L values. Added -4 T_{TAP} values and F_{MINCAL} to Table 39. Revised T_{CINCK}/T_{CKCIN} in Table 40. In Table 41, revised T_{SHCKO}. In Table 42, revised T_{REQ}. Added new -1L values to Table 47. Added and updated values in Table 79.
07/26/10	1.8	Production release of XC6SLX25, XC6SLX25T, XC6SLX100 and XC6SLX100T in the specific speed grades listed in Table 26 and Table 27 using ISE v12.2 software with speed specification v1.11. Added note 7 to Table 2 and moved V_{FS} and R_{FUSE} to a new Table 3. Added I_{HS} and note 4 to Table 4. Added note 1 to Table 28. Added and updated SSO limits per V_{CCO}/GND pairs in Table 34. Added note 3 to Table 47. In Table 54, removed -1L specifications for $CLKOUT_PER_JITT_DV1/2$ and revised $CLKIN_CLKFB_PHASE$ and $CLKOUT_PHASE_DLL$ values. Updated note 3 in both Table 56 and Table 57.
08/23/10	1.9	Updated values for $F_{GTPRANGE1}$, $F_{GTPRANGE2}$, and $F_{GPLLMIN}$ in Table 18. Revised -3 and -4 values in Table 21. Removed the -1L speed grade readback support restriction and note 3 in Table 47.
11/05/10	1.10	Production release of XC6SLX4 and XC6SLX9 in the specific speed grades listed in Table 26 and Table 27 using ISE v12.3 software with speed specification v1.12 for the -2 speed grade available in the 12.3 <i>Speed Files Patch</i>. Added note 3 advising designers of the patch which contains v1.12. In Table 2, added note 4. In Table 4, added note 2. In Table 10, added notes 2 and 3. In Table 44, added note 2. In Table 47, updated symbol for $T_{SMWCKCK}/T_{SMCKCKW}$, changed -1L values for $T_{USERCCLKH}$ and $T_{USERCCLKL}$, and added and revised the modes for F_{MCKCK} and F_{SMCKCK}. In Table 53, redefined and expanded description for $CLKIN_FREQ_DLL$ and rewrote note 3. Updated title of Table 58. Also in Table 78, revised T_{DCD_CLK} for XC6SLX150 and XC6SLX150T. Changed description of T_{PSFD}/T_{PHFD} in Table 71. For the -1L speed grade, updated data sheet to ISE 12.3 software with speed specification v1.05 which revised the values in the following tables: Table 25, Table 28, Table 35, Table 36, Table 37, Table 40 through Table 43, Table 48 through Table 56, Table 62 through Table 78, Table 80, and Table 81. Updated Notice of Disclaimer.